Search Notes

10/716,544

Examiner

Feben M. Haile

Applicant(s)/Patent under Reexamination

MENG, TERESA H.
Art Unit

2616

SEARCHED				
Class	Subclass	Date	Examiner	
370	328	5/2-3/2007	FH	
370	332	5/2-3/2007	FH	
370	465	5/2-3/2007	FH	
370	318	5/2-3/2007	FH	
370	468	5/2-3/2007	FH	
455	522	5/2-3/2007	FH	
455	69	5/2-3/2007	FH	
455	452.1	5/2-3/2007	FH	
455	226.2	5/2-3/2007	FH	
455	115.3	5/2-3/2007	FH	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
Search: power, rate, measur\$3, calcualt\$3, determin\$3, sens\$3, adjust\$3, chang\$3, modify\$3, alter\$3, increas\$3, decreas\$3	5/2-3/2007	FH
Consulted Ian Moore	5/2/2007	FH
Consulted Ian Moore	12/5/2007	FH
Updated Search	12/5 & 7/2007	FH
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